

**Search Notes**

Application/Control No.

10/668,607

Examiner

Khanh V. Nguyen

Applicant(s)/Patent under  
Reexamination

JOO ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	133	11/18/2004	NKV
330	134	11/18/2004	NKV
330	252	12/20/2004	NKV
330	302	11/18/2004	NKV
330	310	11/18/2004	NKV
330	311	11/18/2004	NKV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
CLASSES	ABOVE	4/15/2005	NKV

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	4/15/2005	NKV